

# Experimental report

15/09/2016

**Proposal:** TEST-2596

**Council:** 4/2016

**Title:** Structure of SiO<sub>2</sub> recovered from high pressure

**Research area:**

**This proposal is a new proposal**

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**Samples:** SiO<sub>2</sub>

Instrument	Requested days	Allocated days	From	To
D4	2	2	22/06/2016	24/06/2016

**Abstract:**

## Test Experiment TEST-2596

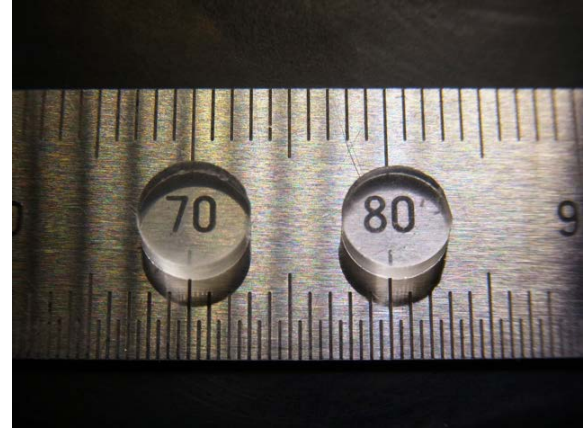
The aim of this work was to establish the mounting setup on D4c for measuring accurate diffraction patterns for small samples of permanently densified glass. For this purpose, samples of permanently densified SiO<sub>2</sub> glass were provided by S Kohara (Center for Materials Research by Information Integration, NIMS, Tsukuba, Japan), along with a sample of “normal” glass having the same dimensions (Fig. 1). The latter refers to a standard piece of SiO<sub>2</sub> glass as prepared at ambient pressure.

Two setups were tested, namely (i) resting the sample on a thin-walled vanadium tube to minimise background scattering, and (ii) holding the sample within a thin-walled vanadium can. The first setup was mechanically unstable and could not be pursued. The second setup avoided this issue, but at the expense of increased background scattering from the vanadium can.

In view of (i) the small sample size and (ii) the small scattering and absorption cross-sections of Si and O, attenuation and multiple scattering corrections were not made. The data sets were normalised using the calculated self-scattering cross section, and inelasticity corrections were made by using the method described by Yarnell et al. (Phys. Rev. A **7** (1973) 2130). The resultant  $S(q)$  functions are shown in Fig. 2 where

$$S(q) = \frac{\sum_{\alpha} \sum_{\beta} c_{\alpha} c_{\beta} b_{\alpha} b_{\beta} [S_{\alpha\beta}(q) - 1]}{\langle b \rangle^2},$$

$c_{\alpha}$  and  $b_{\alpha}$  are the atomic fraction and bound coherent neutron scattering length of chemical species  $\alpha$ ,  $\langle b \rangle = \sum_{\alpha} c_{\alpha} b_{\alpha}$  is the average scattering length, and  $S_{\alpha\beta}(q)$  is a partial structure factor.



Before	After
RT, 0 GPa	1200 °C, 7.7 GPa

Fig. 1. Samples of “normal” SiO<sub>2</sub> glass (left) and 23% densified SiO<sub>2</sub> glass (right) with an approximate diameter of 5.7 mm and thickness of 1.5 mm.

A separate experiment was performed using a solid cylindrical rod of “normal” SiO<sub>2</sub> glass in a regular setup with a beam height of 4 mm, and a full data analysis procedure was employed (Salmon et al. Phys. Rev. B **58** (1998) 6115). As shown in Fig. 2, the measured total structure factors  $S(q)$  for the small sample and for the silica rod are identical within the statistical error.

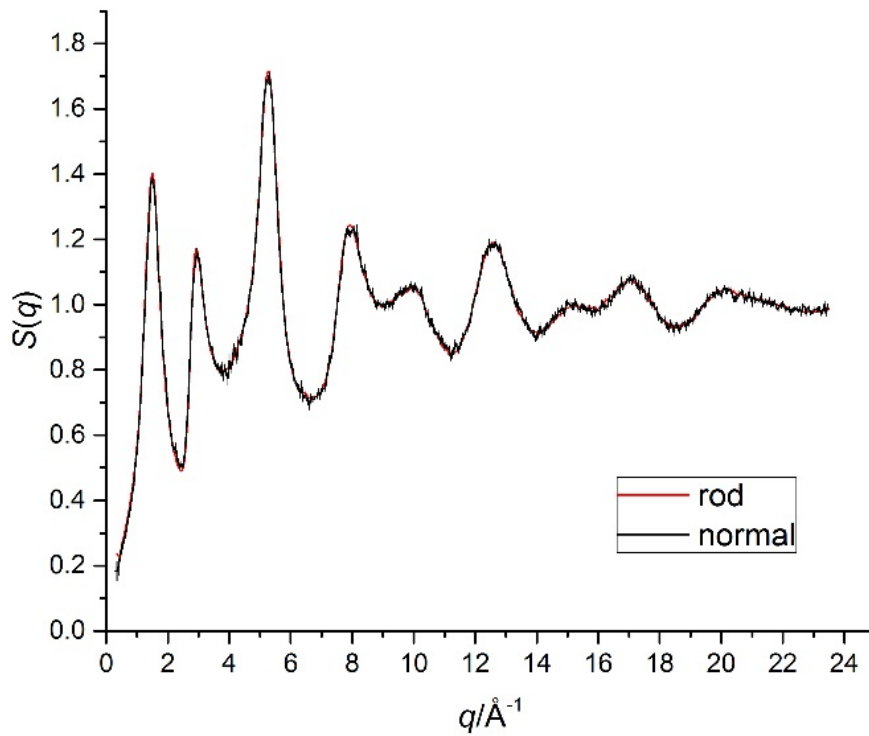


Fig. 2. The  $S(q)$  function measured for a small sample of “normal” SiO<sub>2</sub> in a thin-walled vanadium can, compared to the  $S(q)$  function measured for a “normal” SiO<sub>2</sub> rod in a regular scattering geometry with no container. The data sets are identical within the statistical error.